

Fig. 1
(Related Art)

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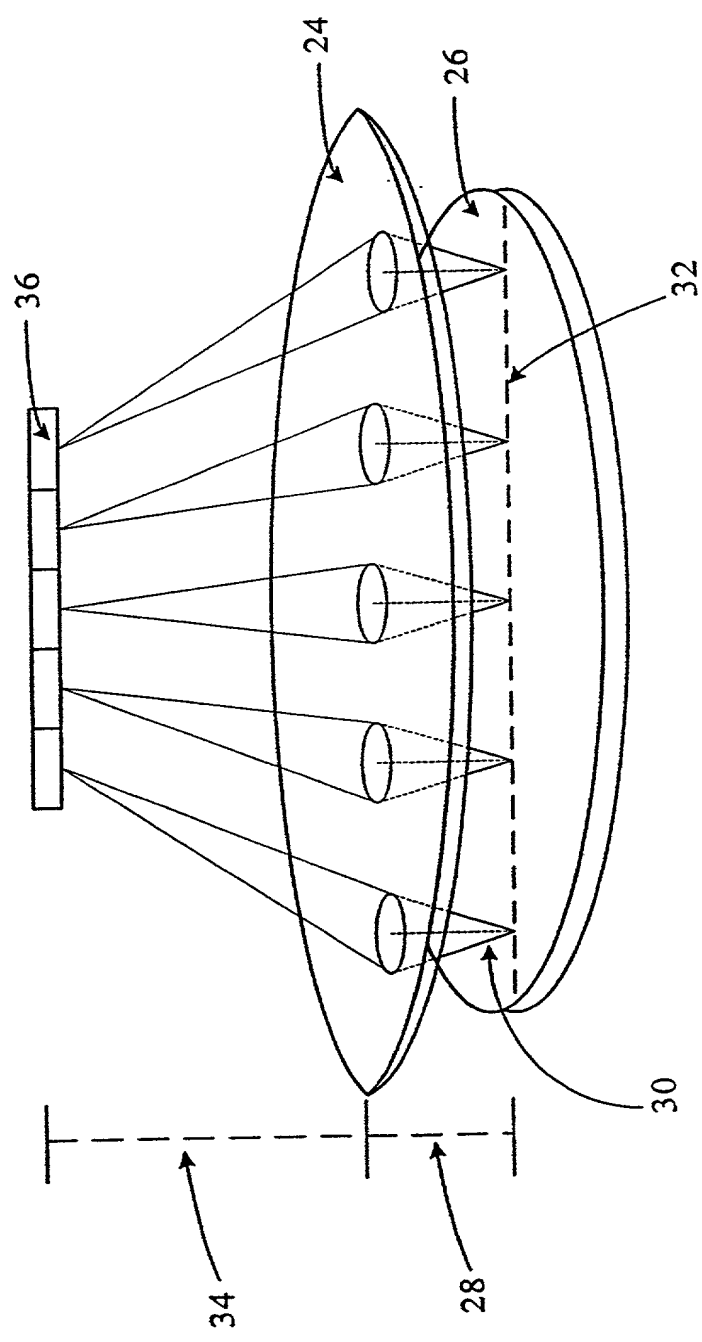
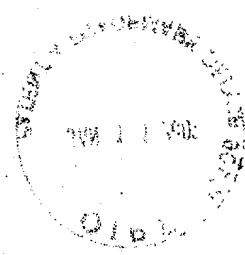


Fig. 2
(Related Art)

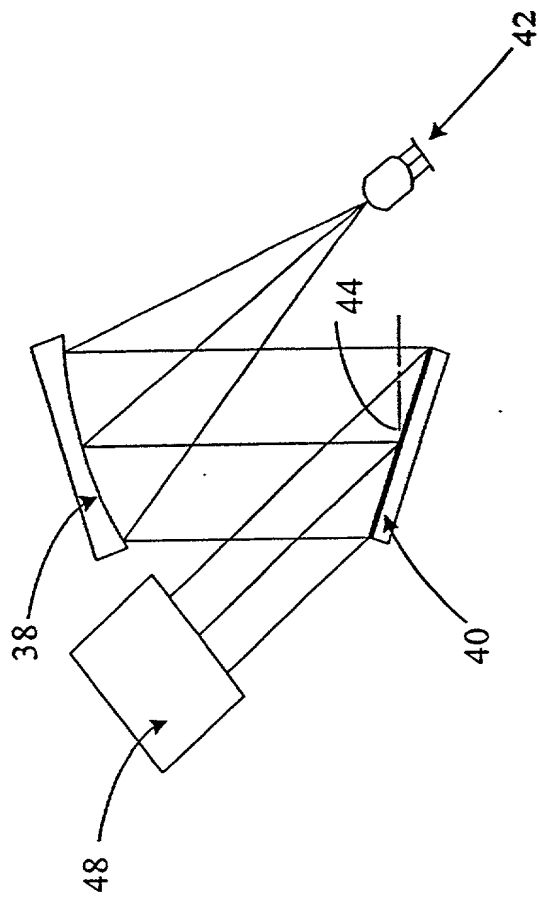
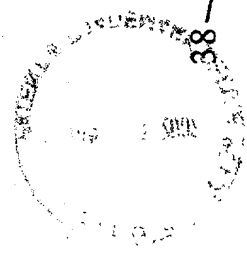


Fig. 3A
(Related Art)

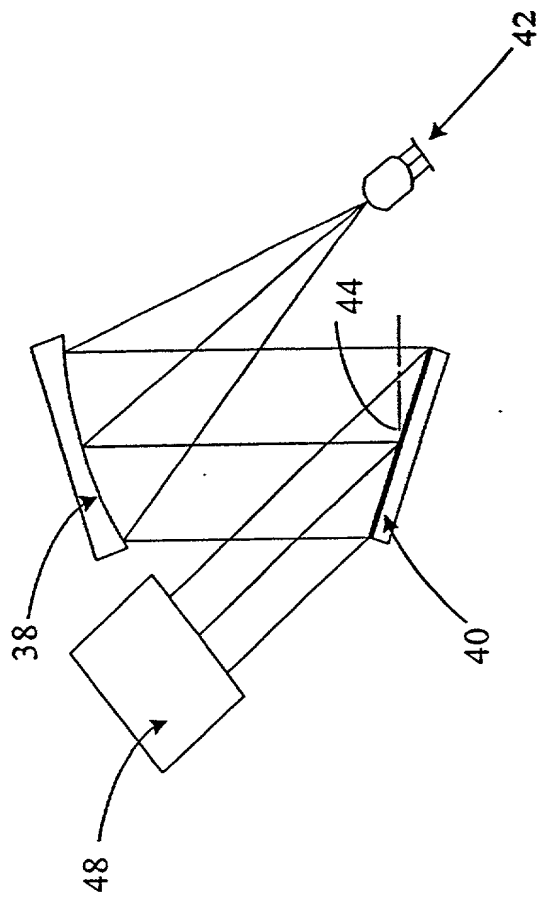


Fig. 3B
(Related Art)



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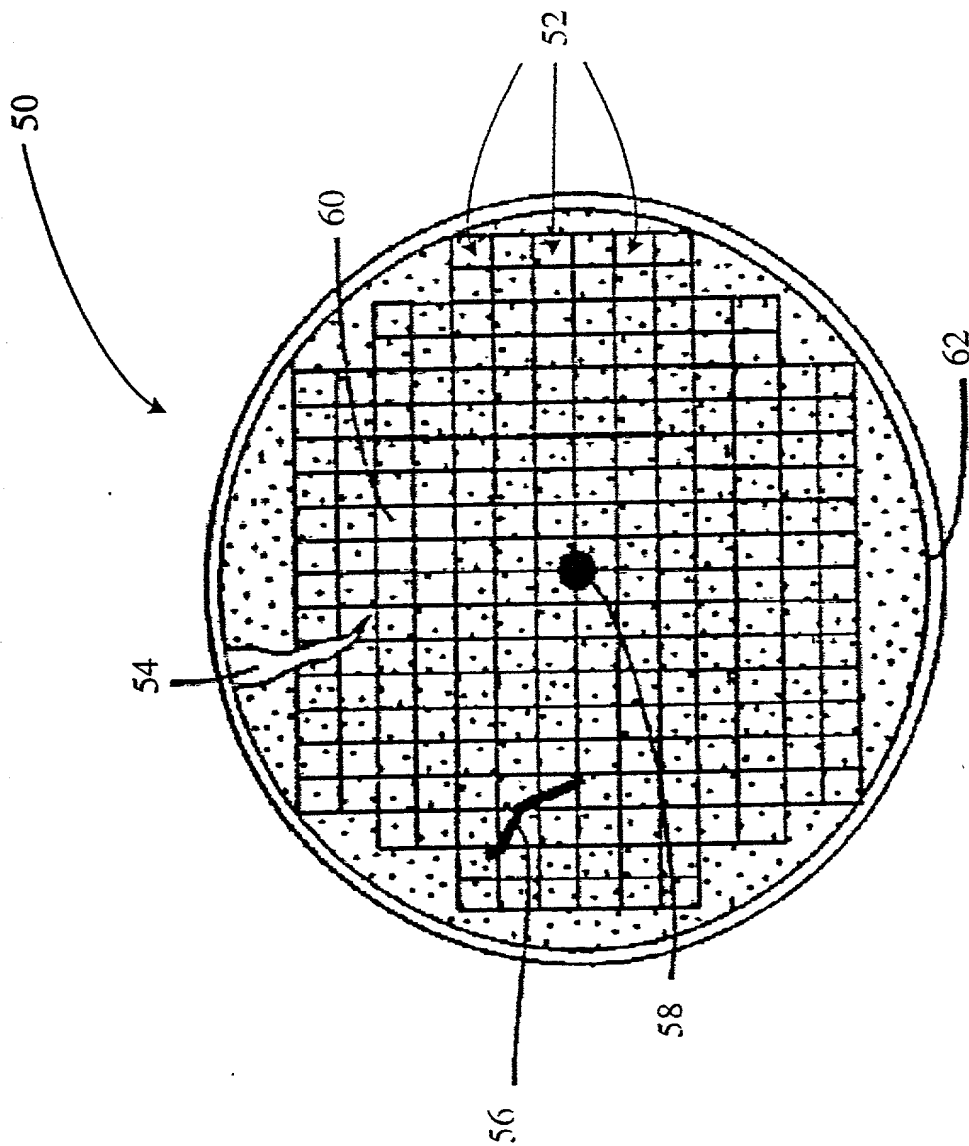


Fig. 4

FIG. 5

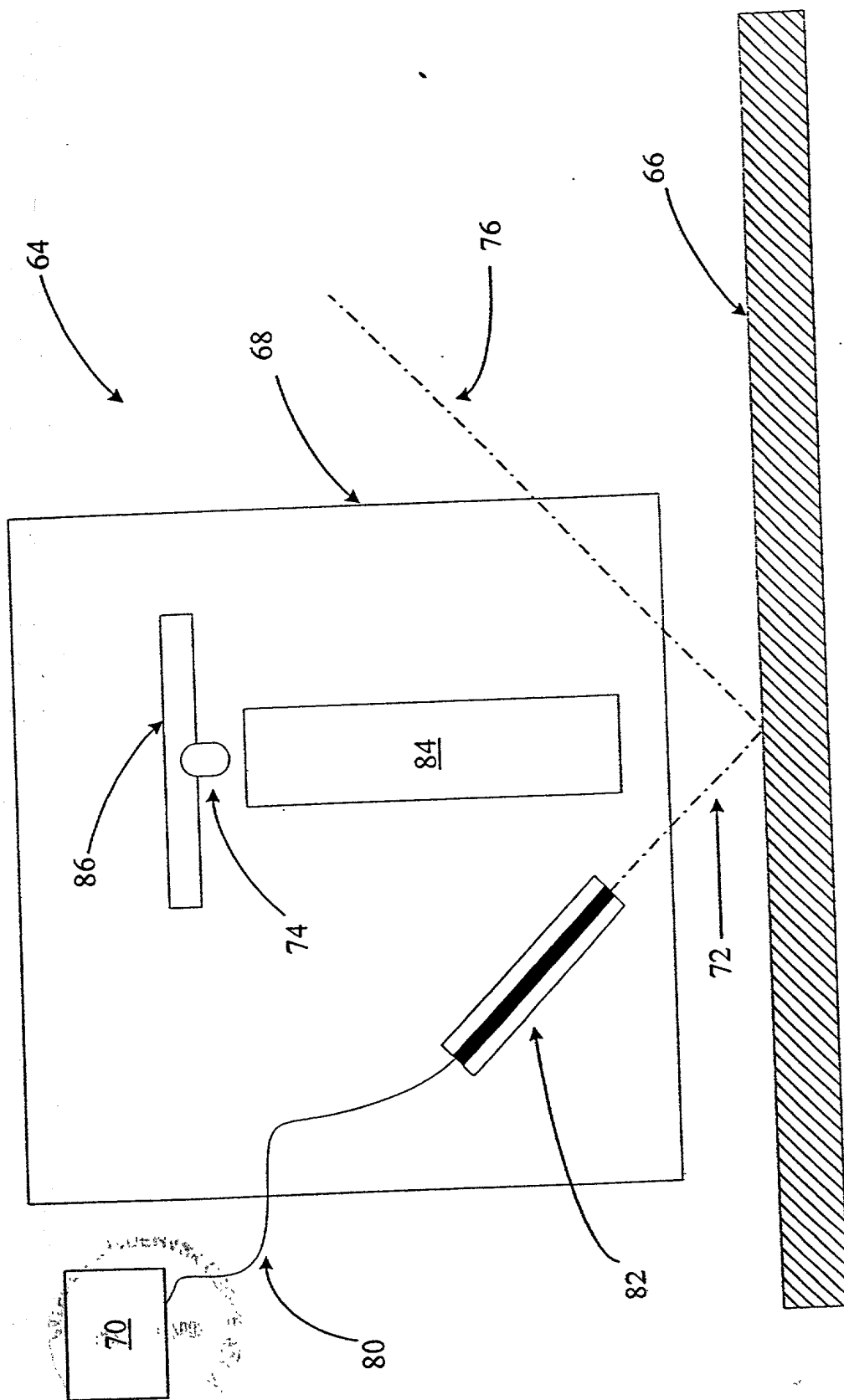


Fig. 5

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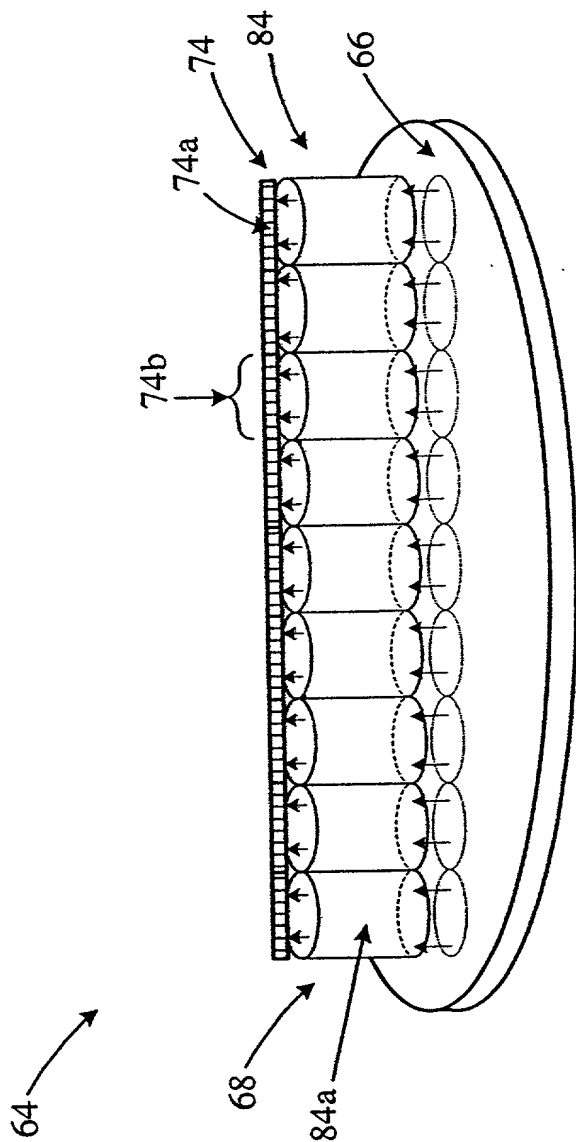


Fig. 6

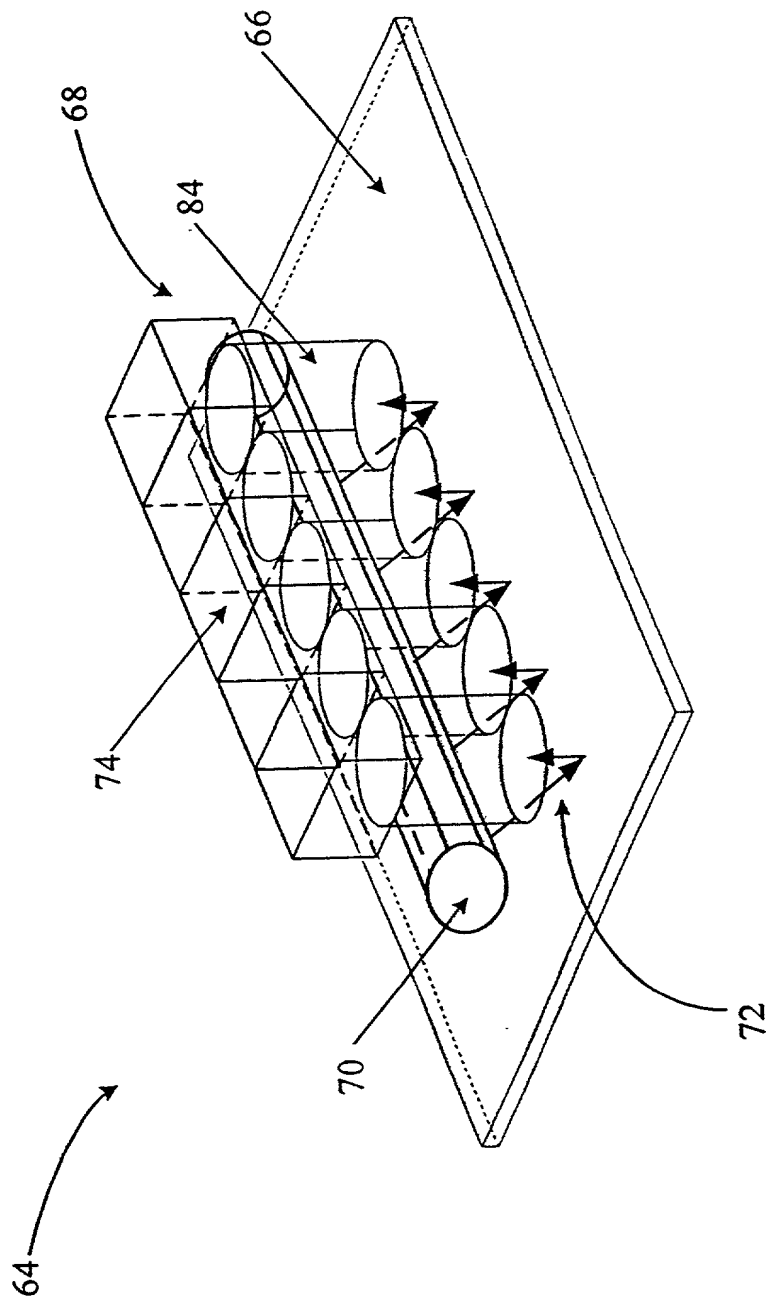
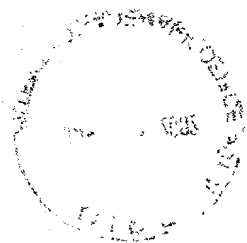


Fig. 7

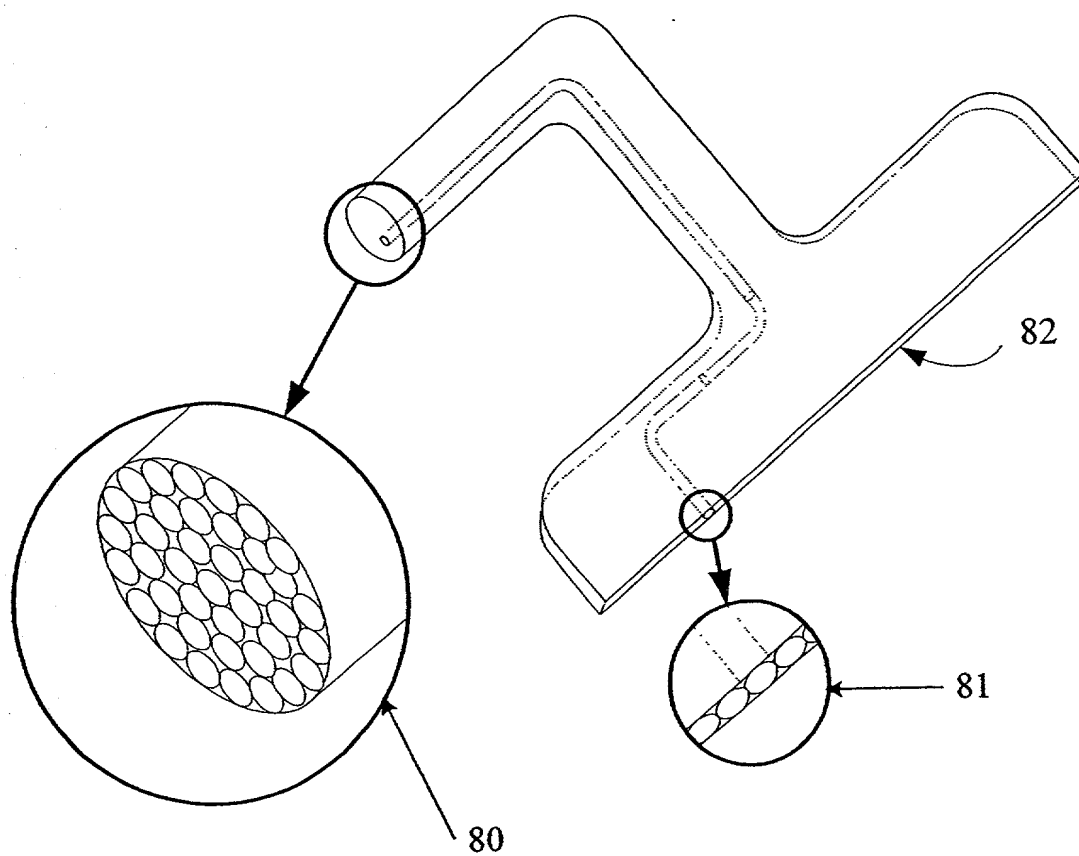
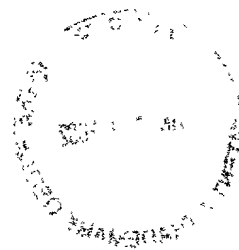


Fig. 7a

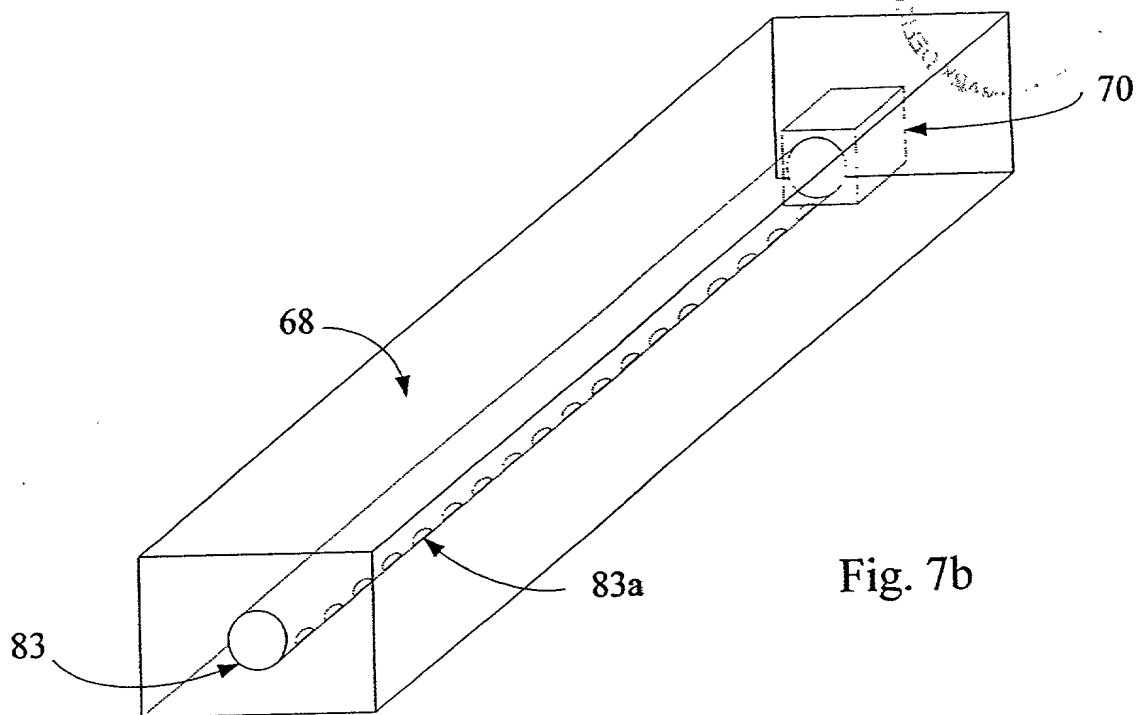


Fig. 7b

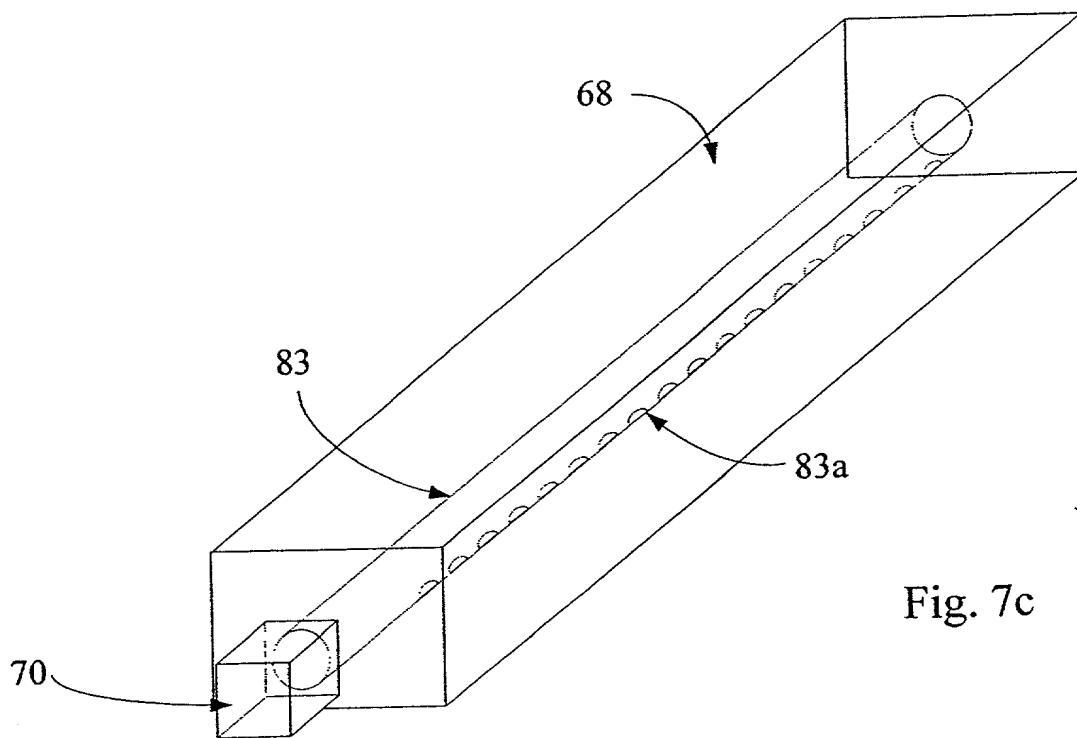


Fig. 7c

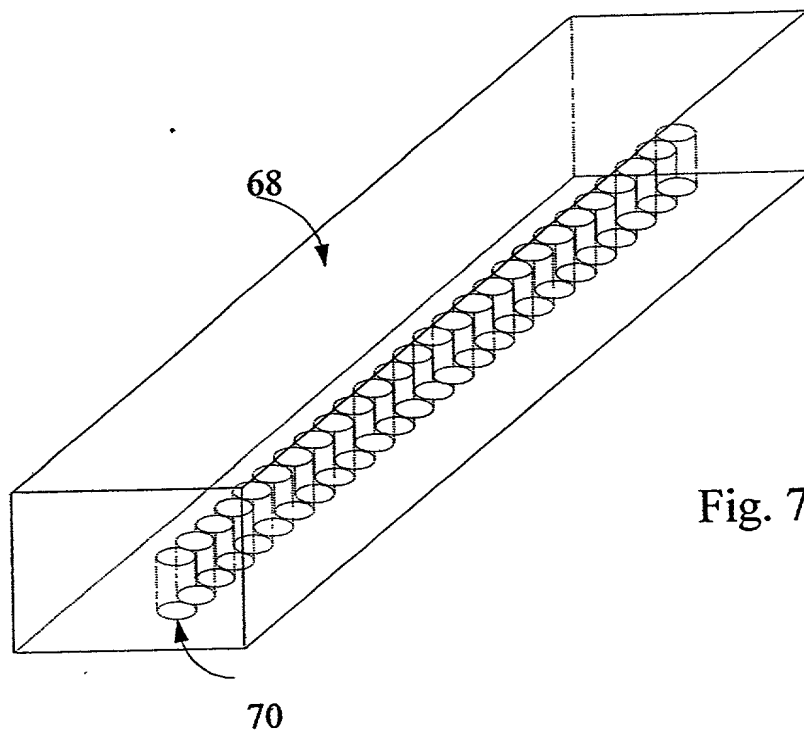


Fig. 7d

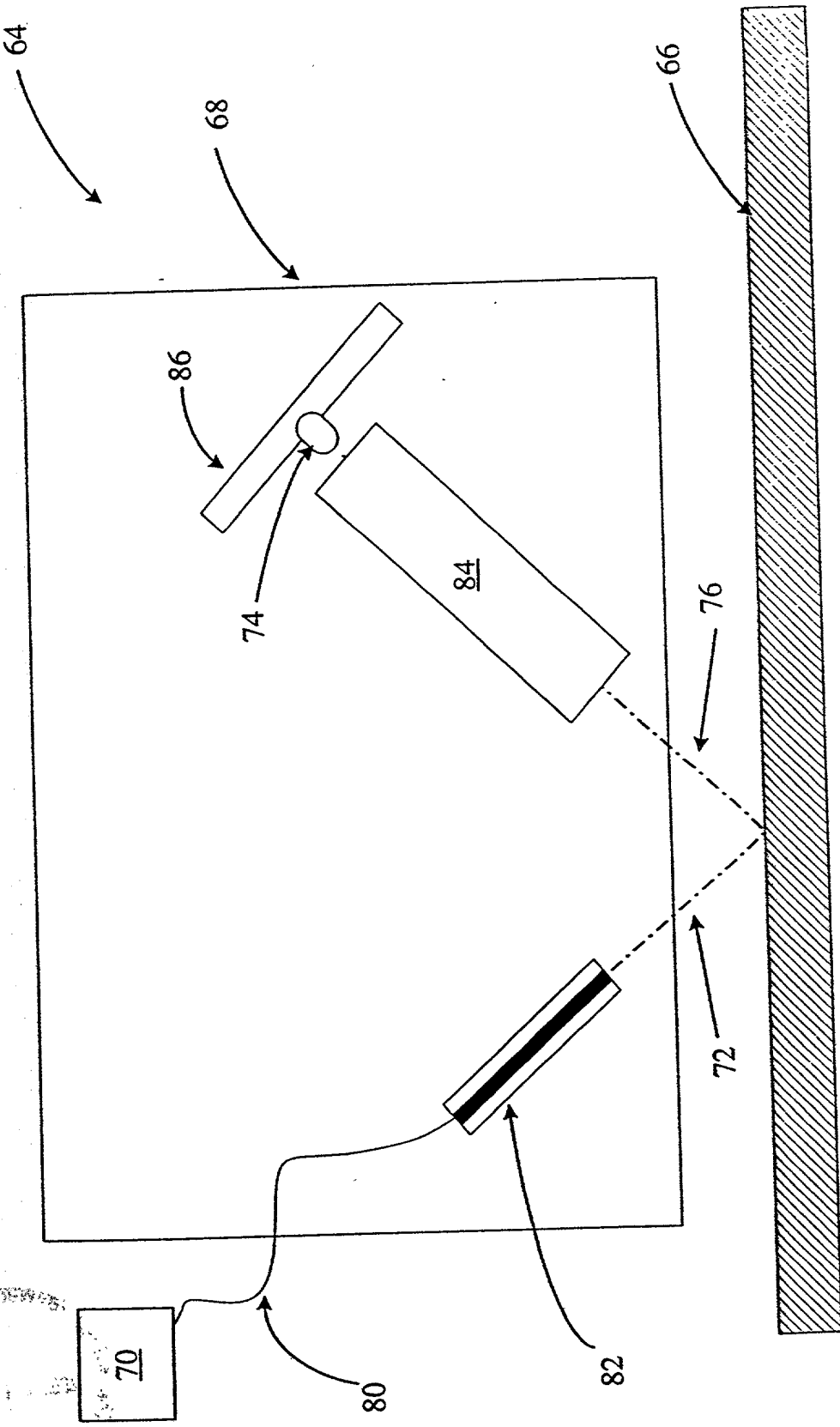


Fig. 8

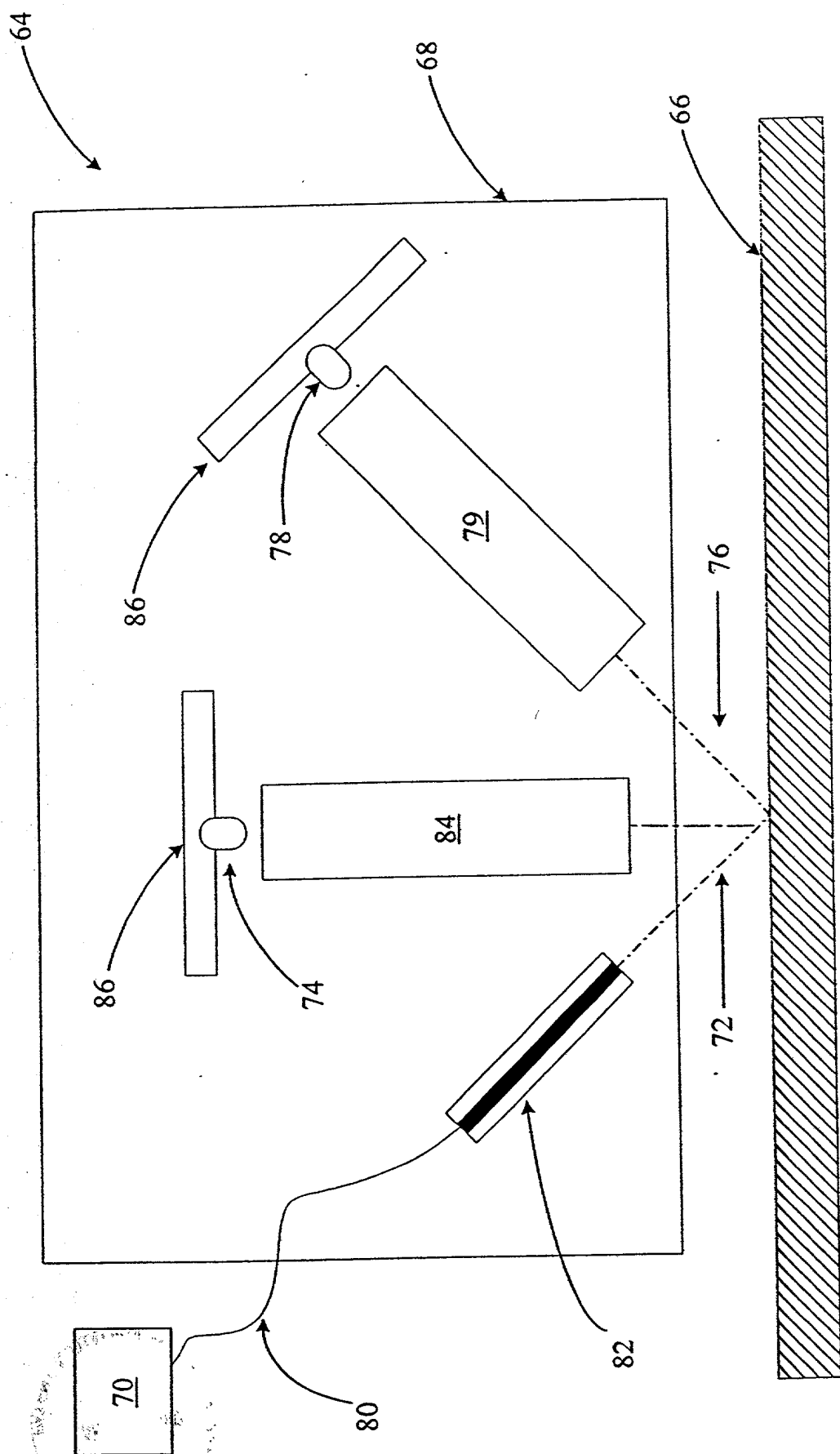


Fig. 9

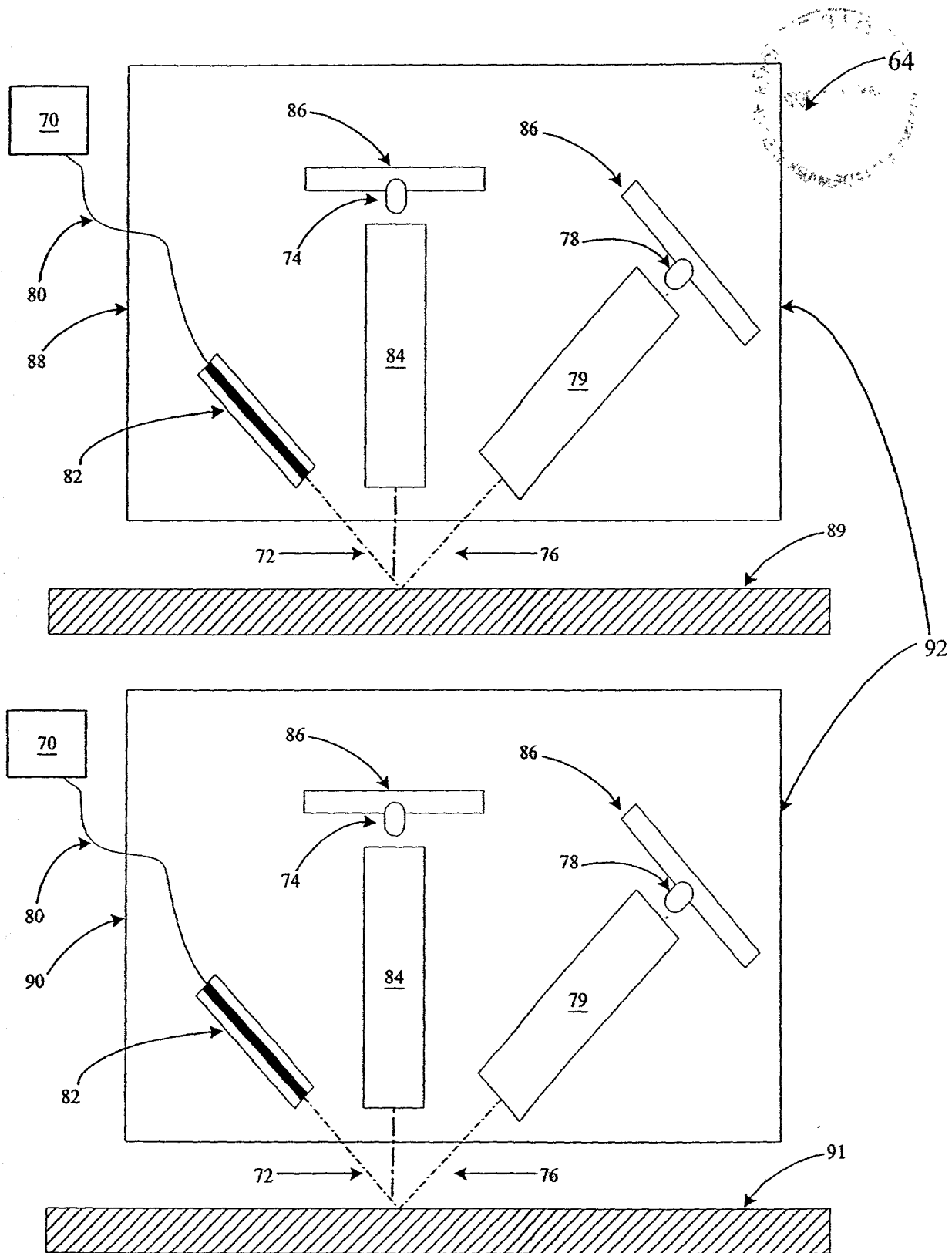


Fig. 10

FIG. 11 is a schematic diagram of a system for measuring the thickness of a material.

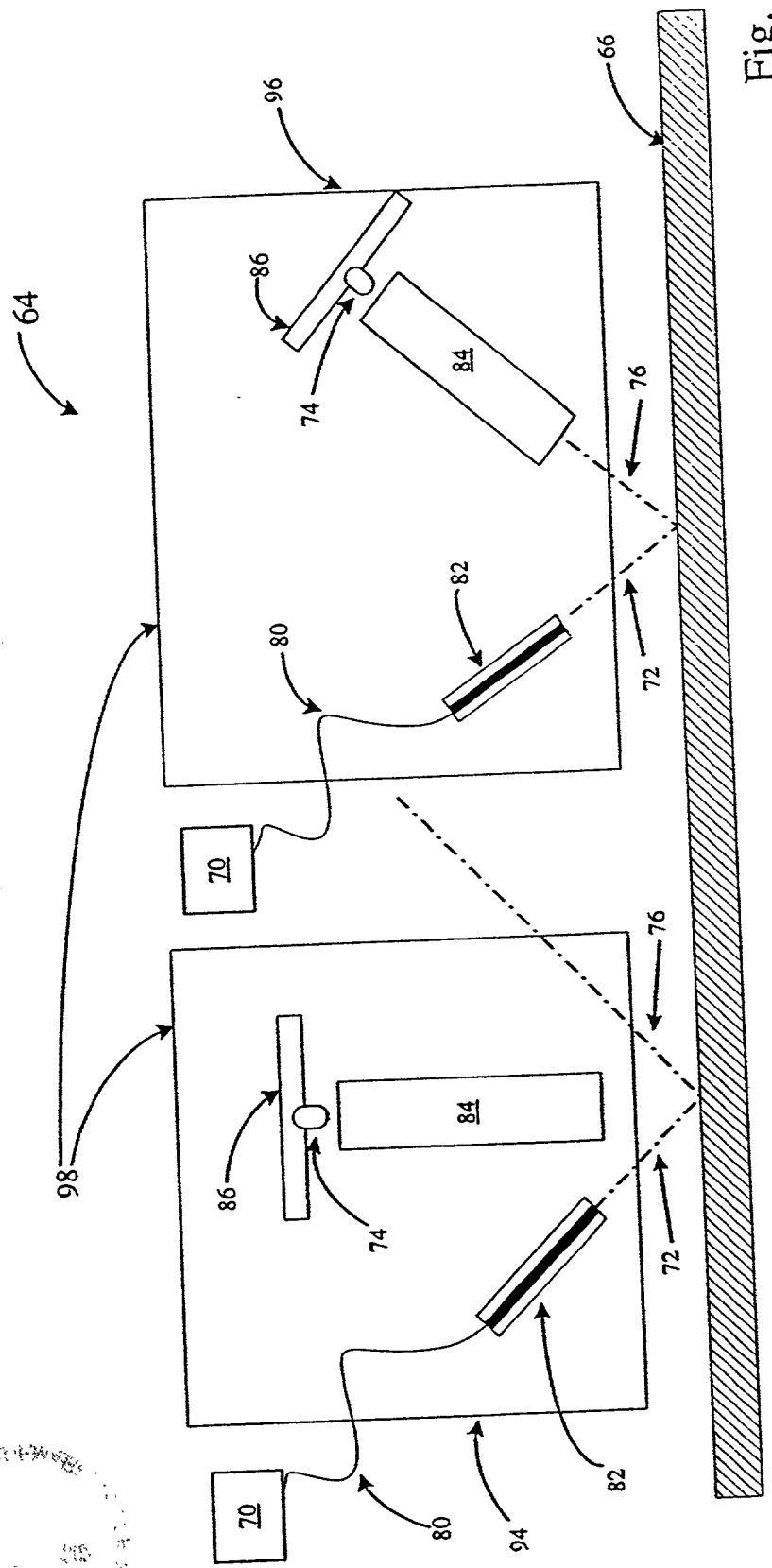


Fig. 11

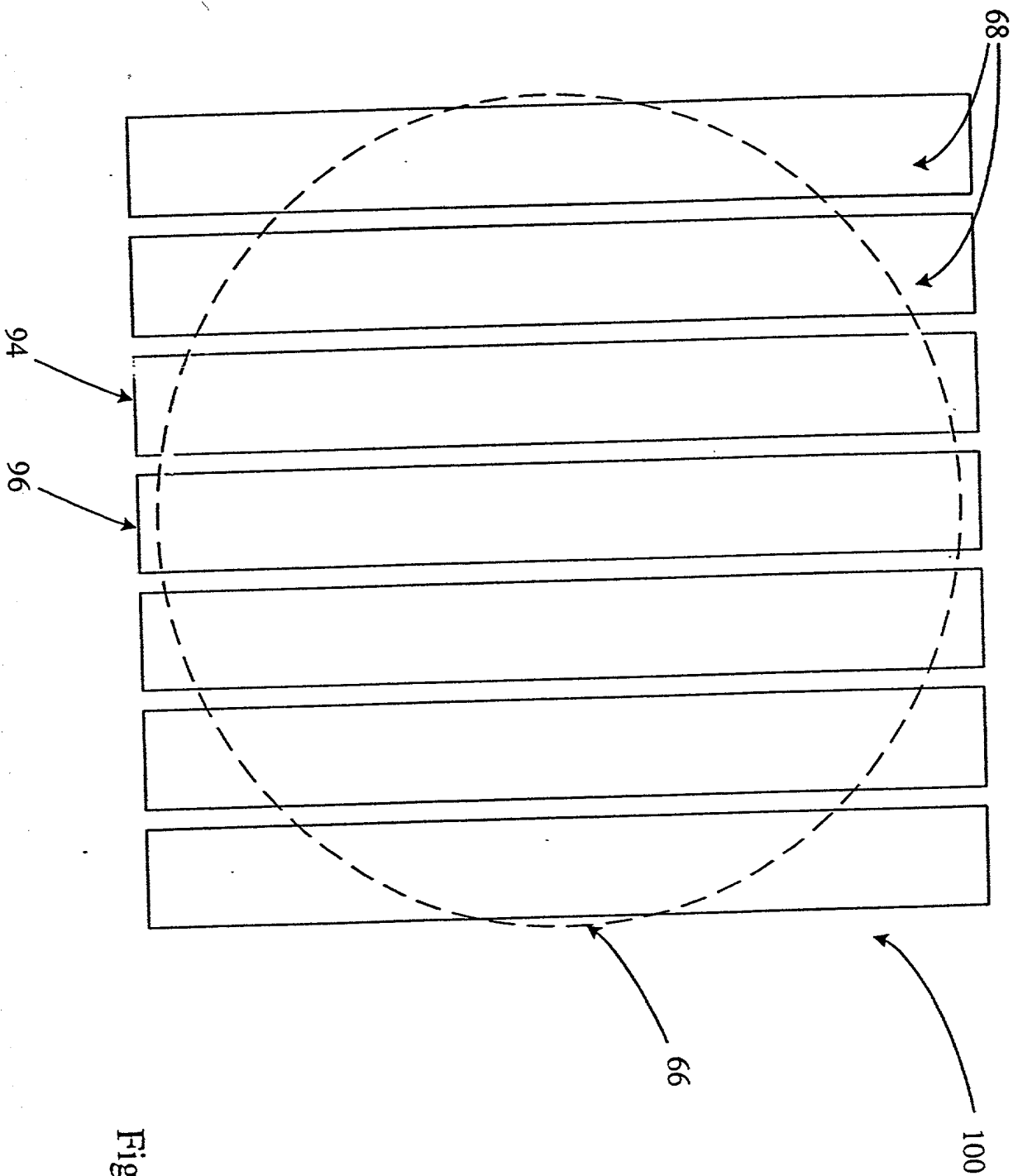


Fig. 12

FIG. 13 is a schematic diagram of a device 100 in a first state. The device 100 includes a plurality of elongated members 66, 68, 94, 96, and 102. The members 66, 68, 94, and 96 are arranged in a row, and the member 102 is positioned below them. The members 66, 68, 94, and 96 are connected to each other by a common member 102. The members 66, 68, 94, and 96 are arranged in a row, and the member 102 is positioned below them. The members 66, 68, 94, and 96 are connected to each other by a common member 102.

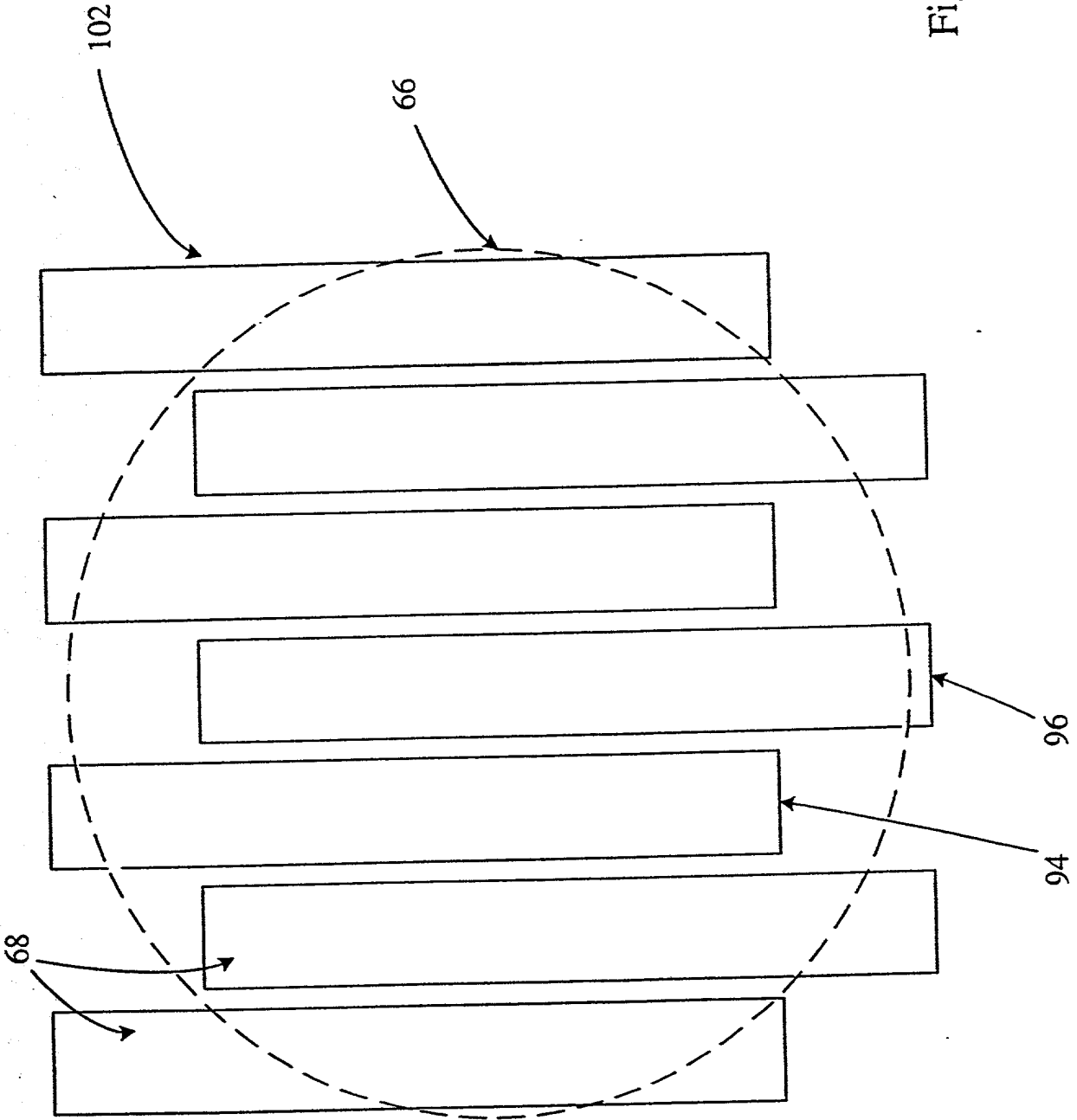


Fig. 13

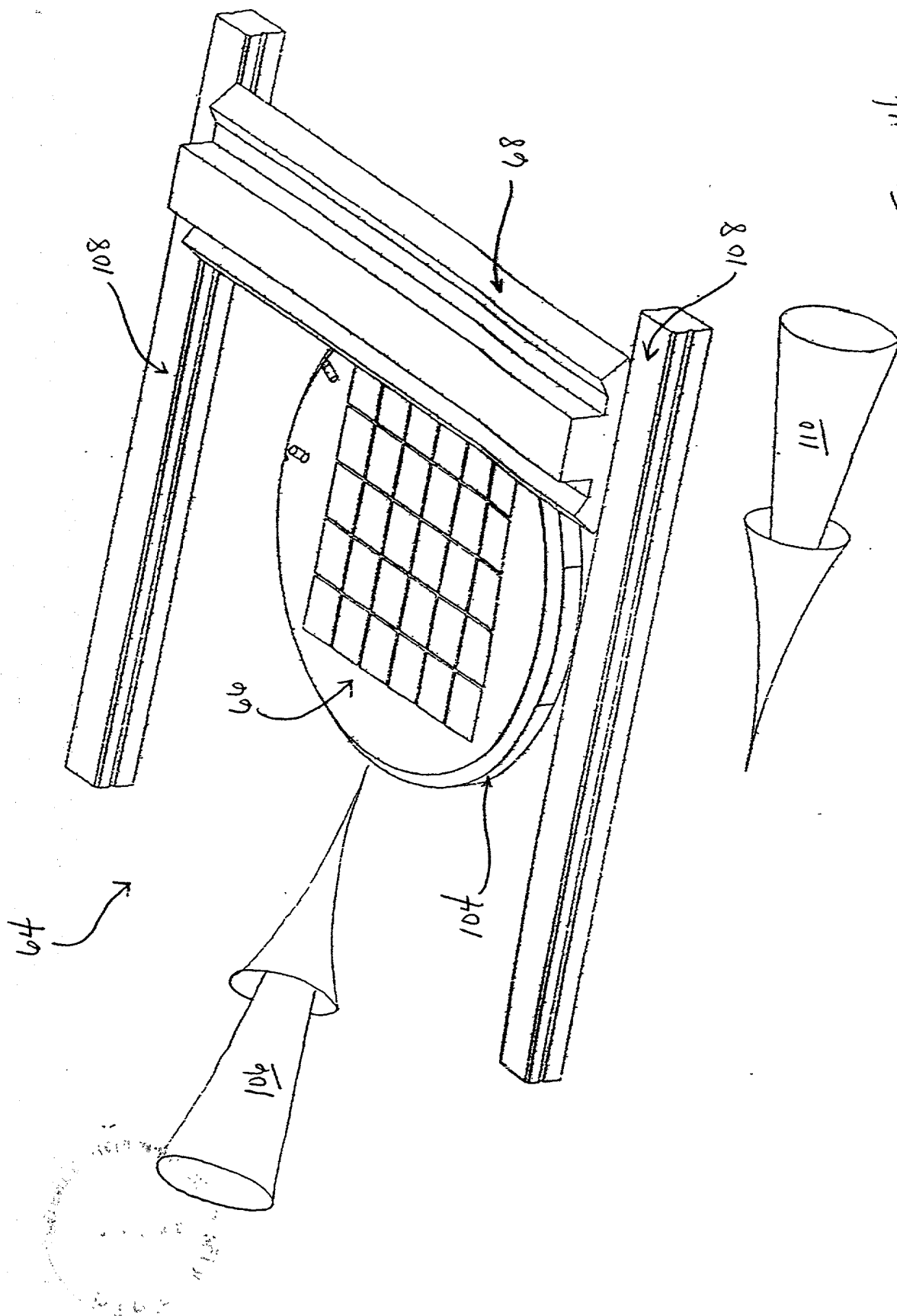
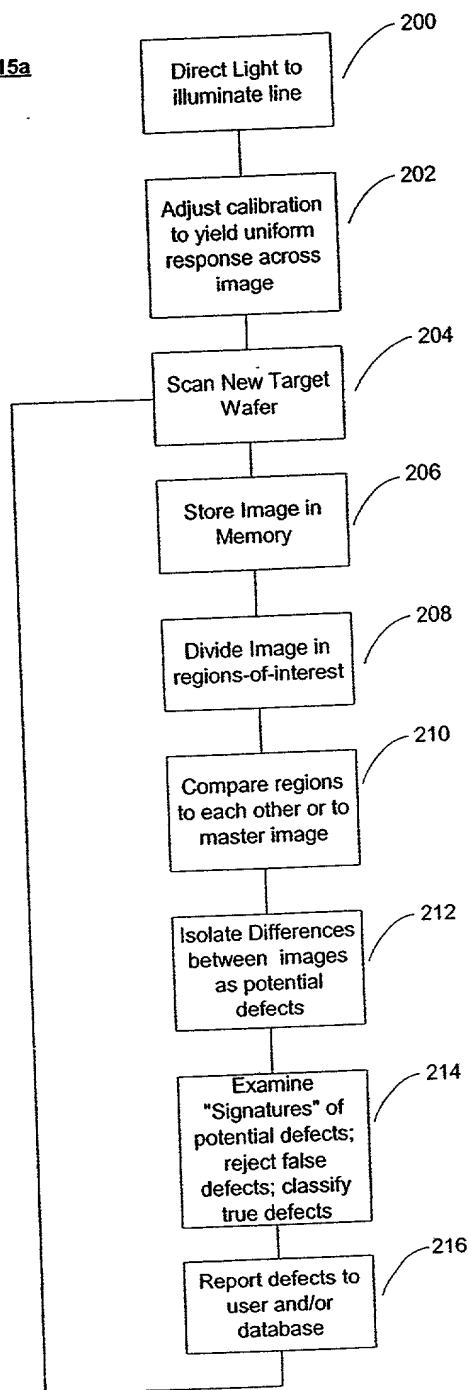


Fig. 14

FIGURE 15a



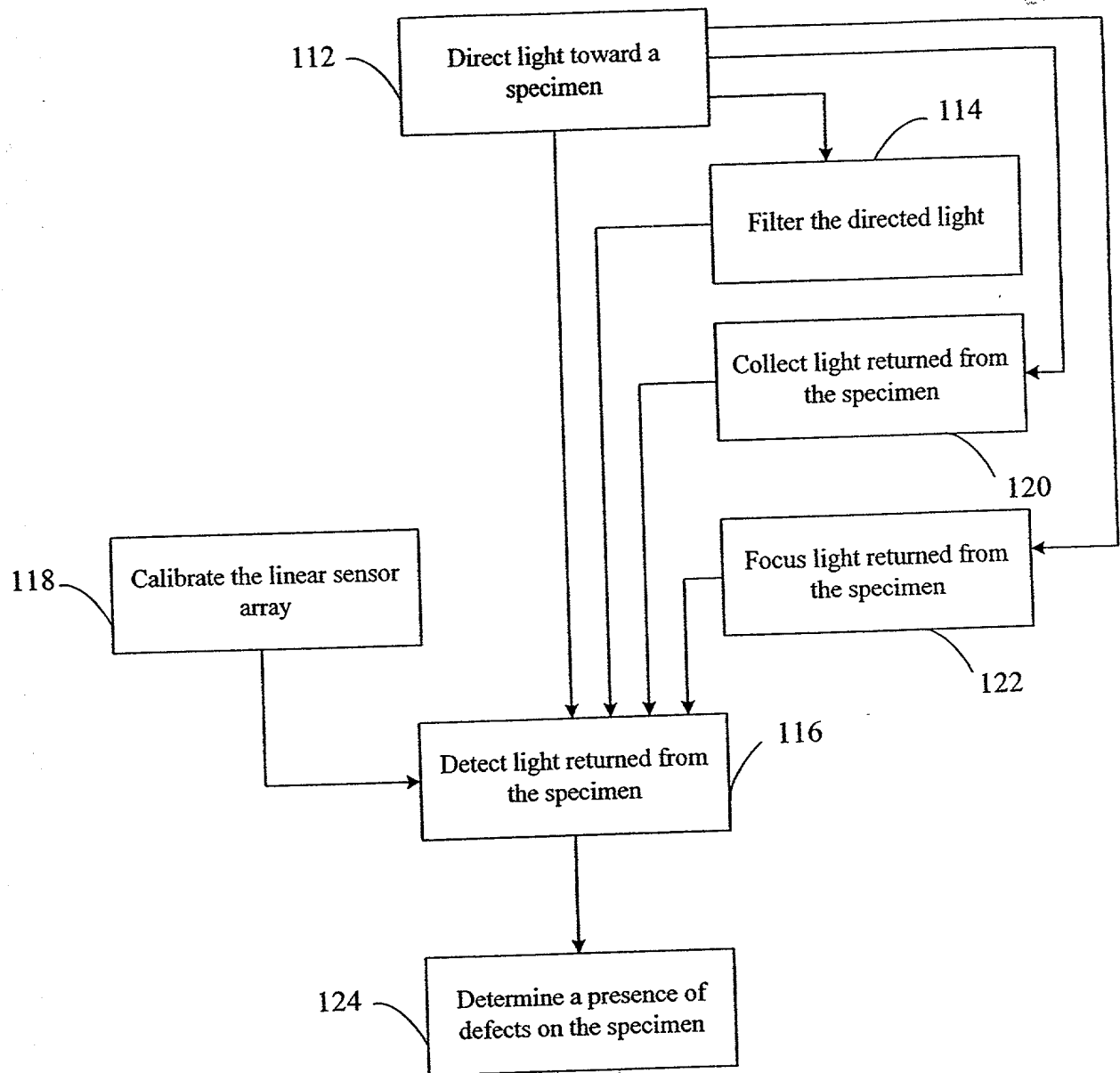


Fig. 15b

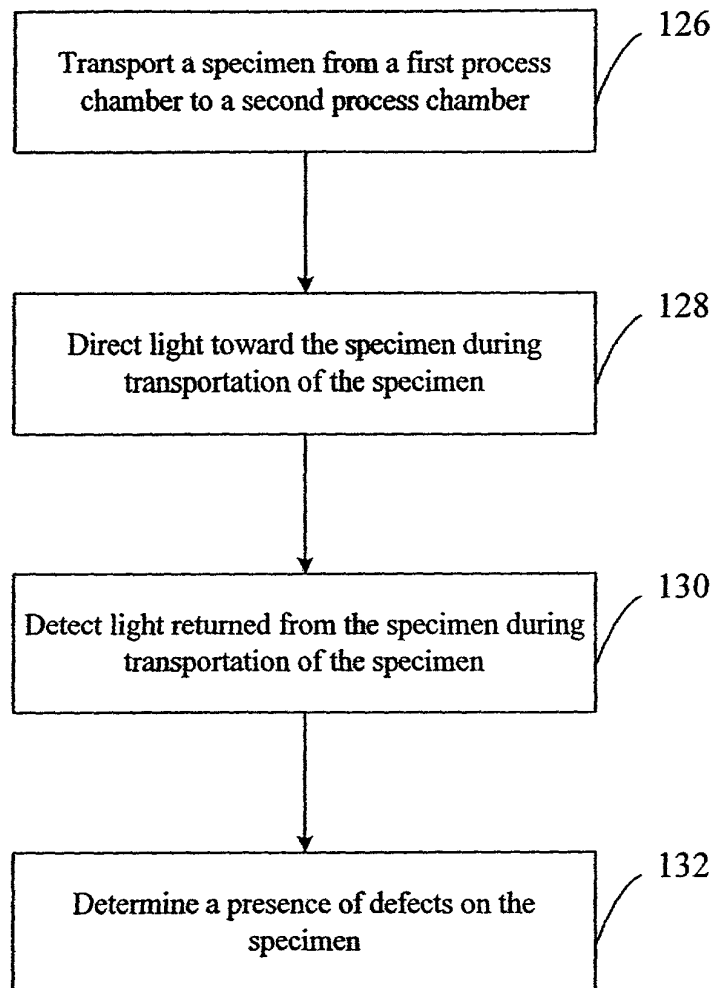


Fig. 16

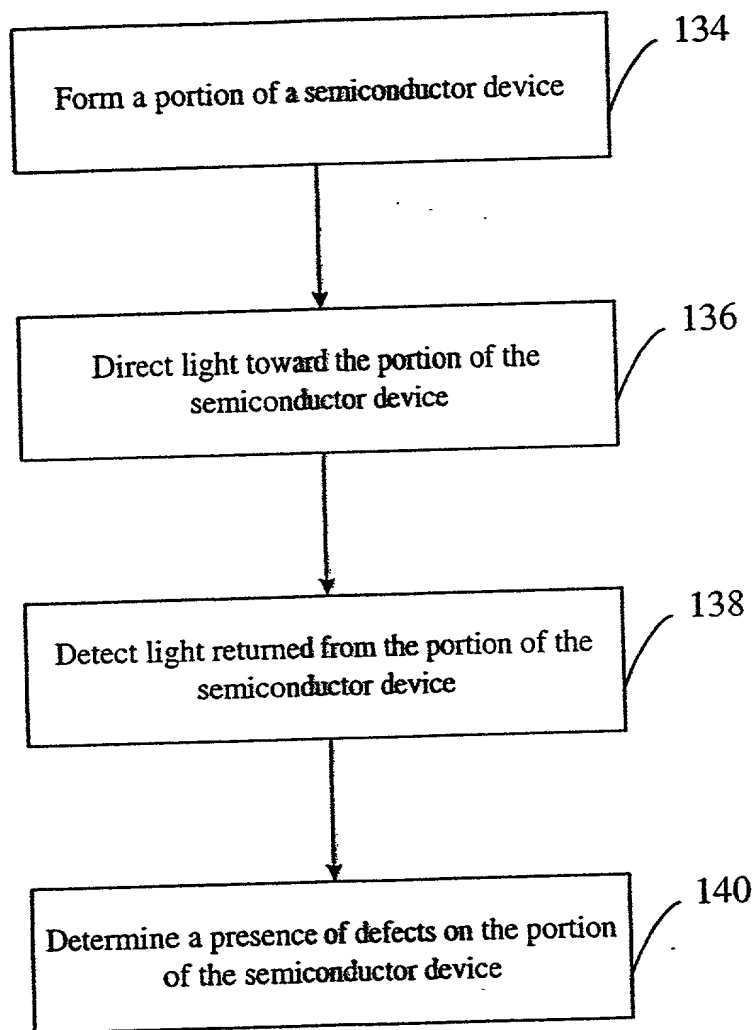


Fig. 17

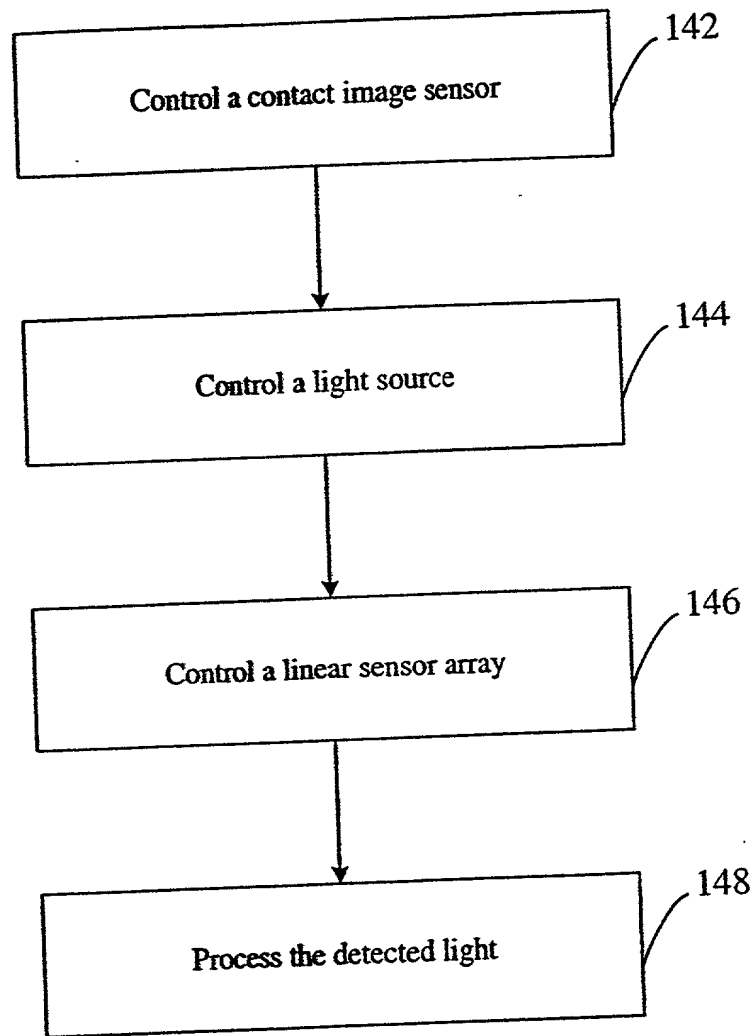


Fig. 18

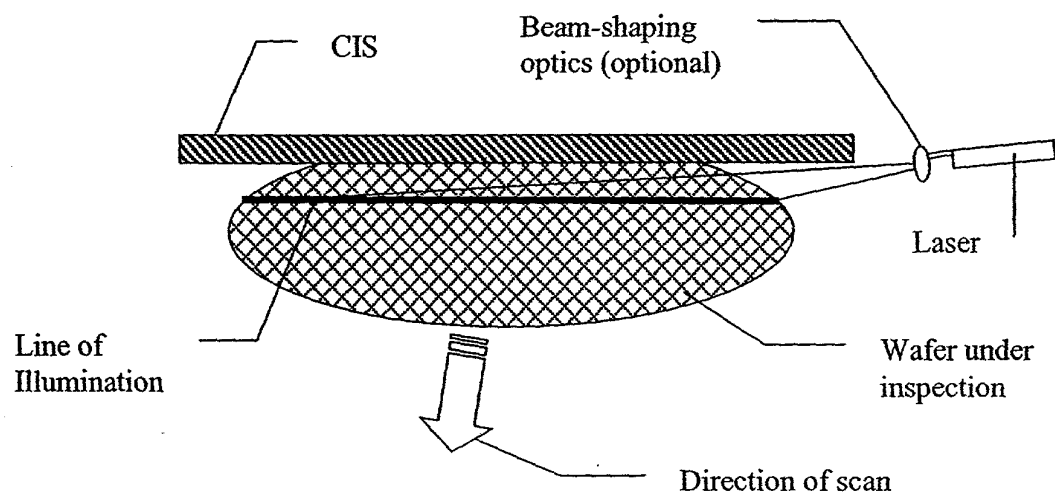


FIGURE 19